



Product Safety Engineering Society
Taipei Chapter

High Frequency Voltage Stress

Presented by: Flore Chiang

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2.10.1.1 Frequency

The insulation requirements given in 2.10 are for frequencies up to 30 kHz. It is permitted to use the same requirements for insulation operating at frequencies over 30 kHz until additional data is available.

10 Insulation requirements

The insulation requirements given in this standard are for frequencies up to 30 kHz. It is permitted to use the same requirements for insulation operating at frequencies over 30 kHz until additional data are available.

Now the additional data is available!





PSES

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ground rules:

1. intro to PD.
2. experimental results.
3. comparison with current practice.
4. **why** different?
5. **how** air and solid dielectrics behave under high frequency stress?



IEC 60664-4:2005 (2nd Ed.)

- Any type of periodic voltages with a **fundamental frequency** (f_0) above 30 kHz and up to 10 MHz

Key phenomenon = **partial discharge (PD)**

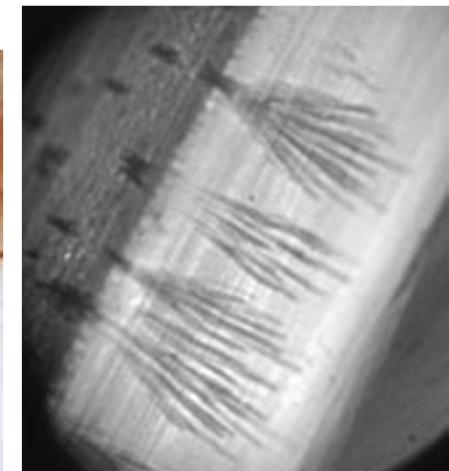
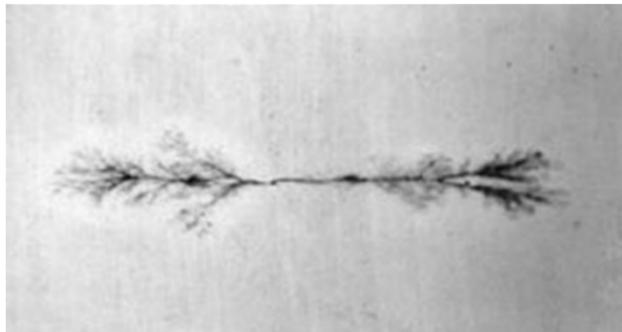
- Its deteriorating effect is aggravated roughly in proportionally to the frequency



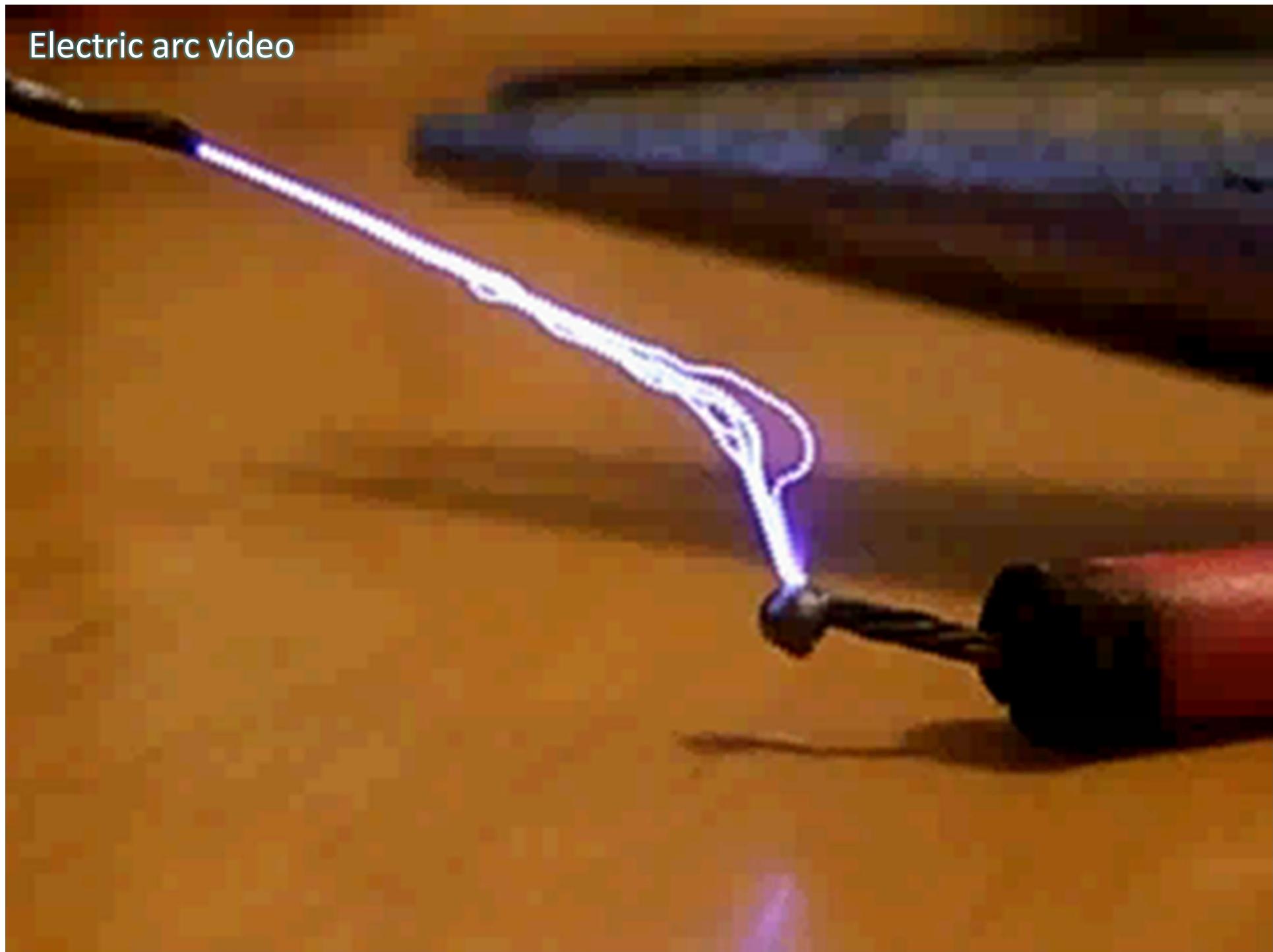
partial discharge (PD)

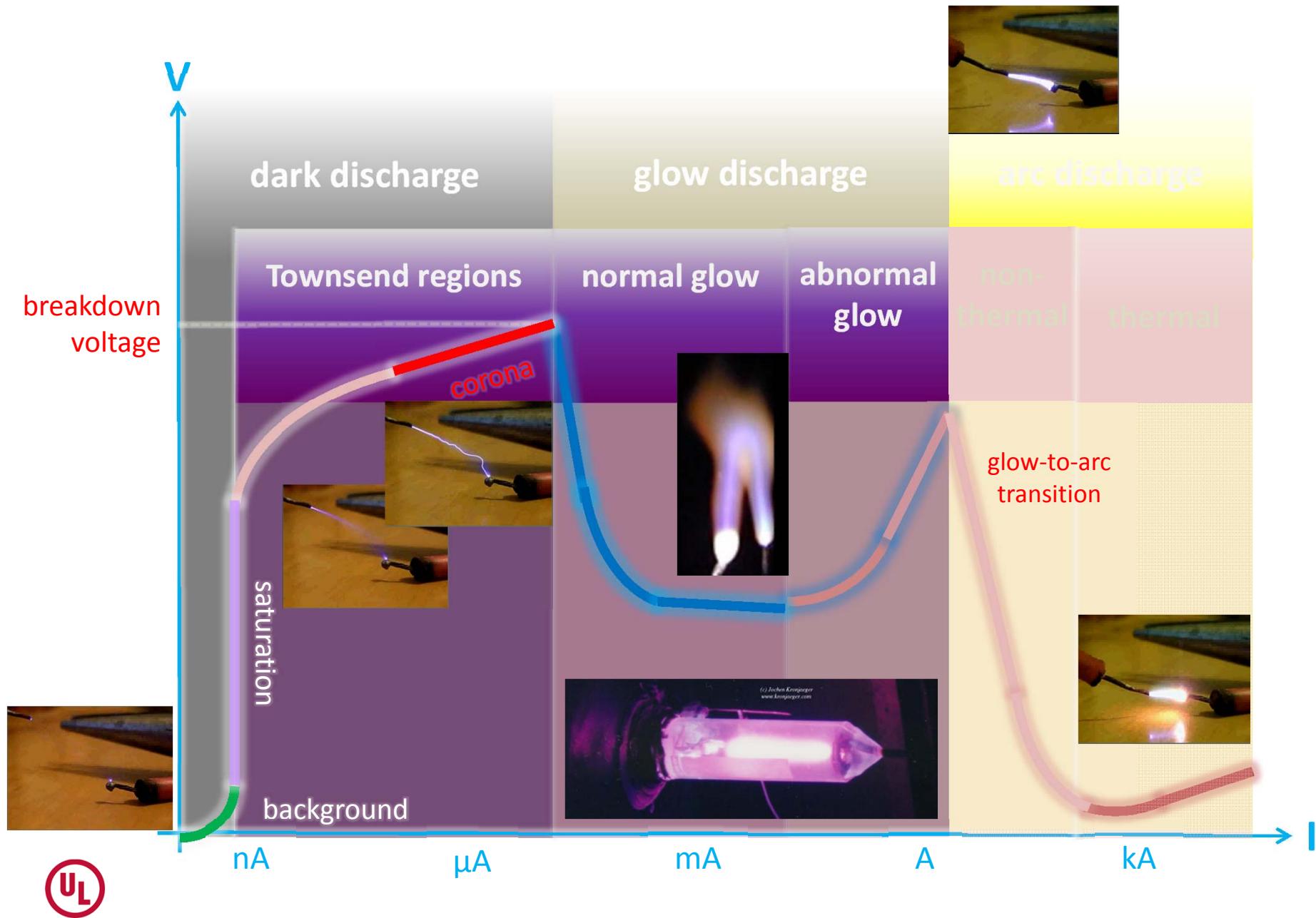
is a localized discharge within a solid or fluid dielectric system, restricted to only a part of dielectric material thus *only partially bridging the electrodes*, and is typically observed:

- in cavities, voids (bubbles) or gaps;
- between interfaces of different dielectric properties;
- at sharp electrode edges or protrusions.



Electric arc video





Slow motion video of lightning

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ztresearch.com

CLEARANCES



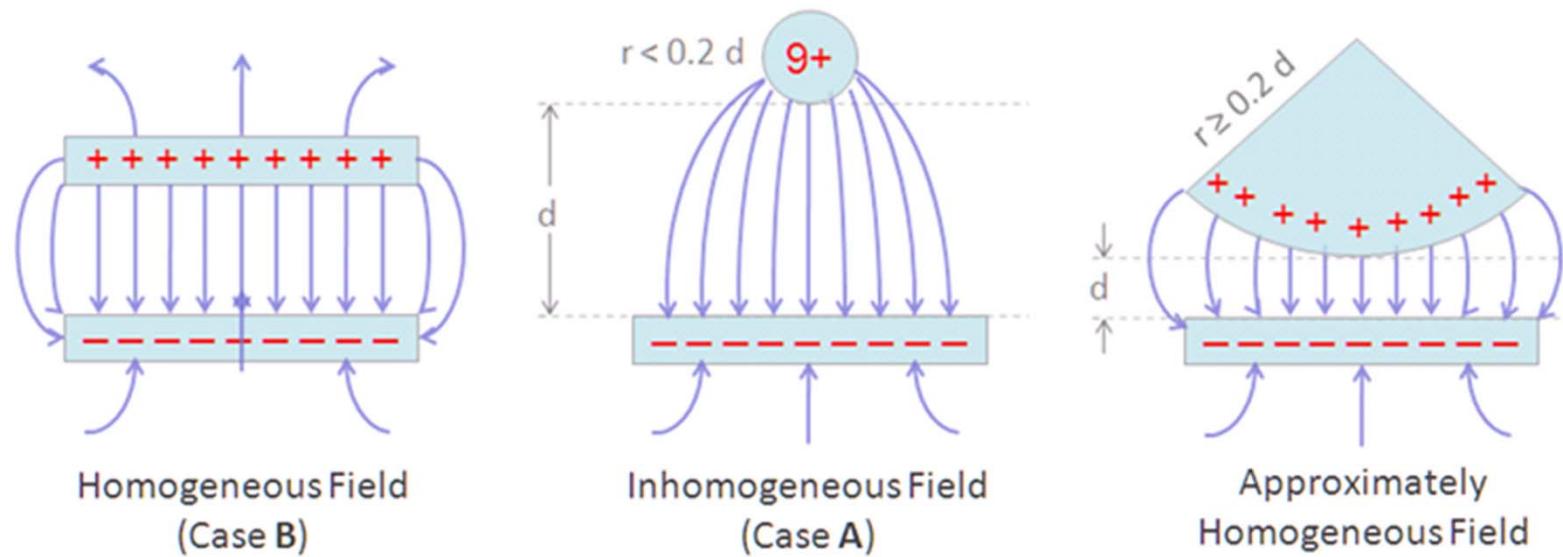
field homogeneity

inhomogeneous field (point-to-plane).....Case A

homogeneous field (plane-to-plane)..... Case B

approximately homogeneous field

- when the radius of curvature of the conductive parts is equal or greater than **20 %** of the associated clearance.



**figure A.1 — breakdown
at high frequency in air
at atmospheric pressure,
homogeneous field,
50 Hz – 25 MHz**

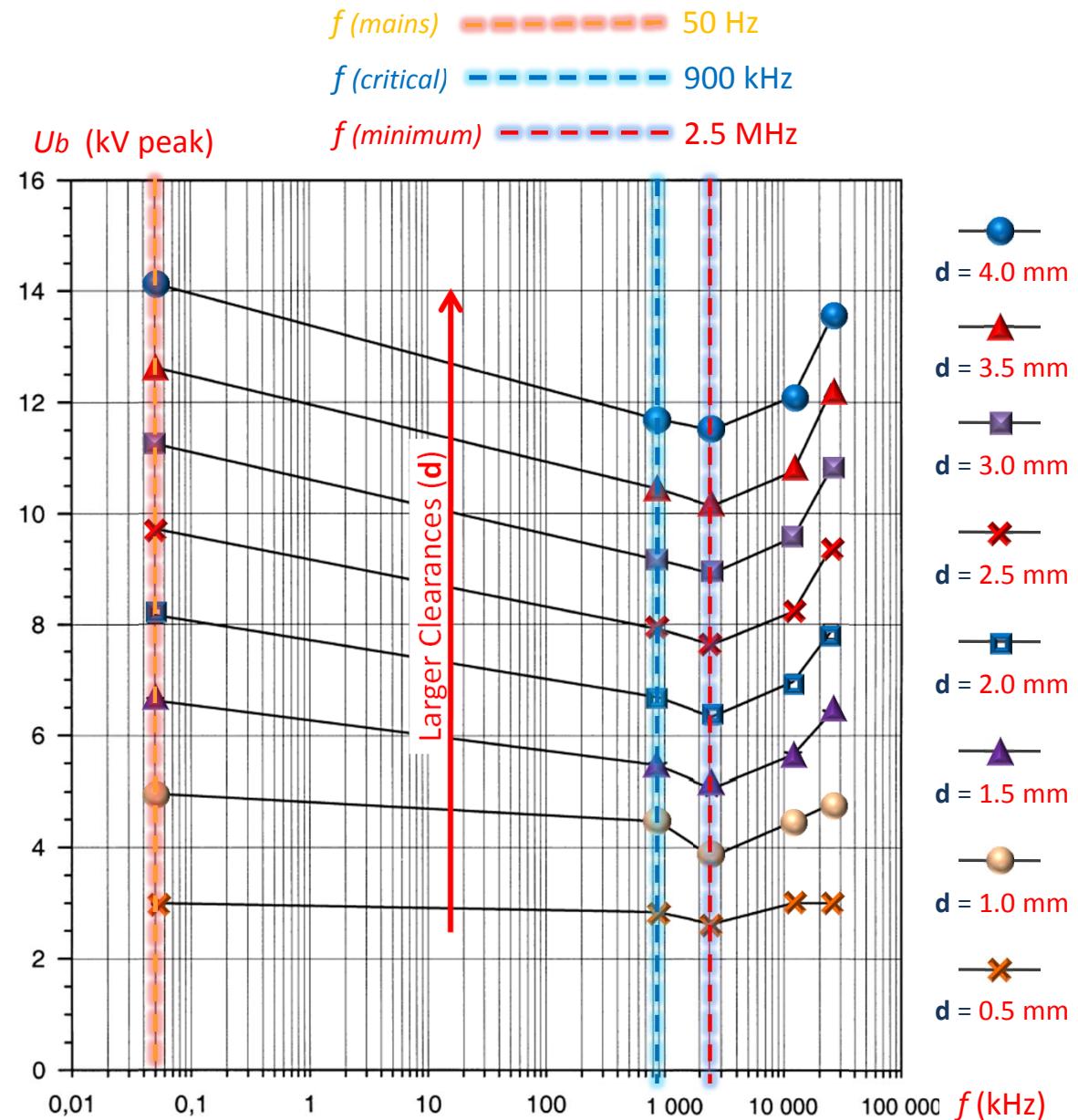
breakdown voltage (U_b)
is frequency-dependent.

U_b degrades at 900 kHz,
i.e., critical frequency.

worst-case scenario
at 2.5 MHz, i.e., $f_{(min)}$

~80% retention rate

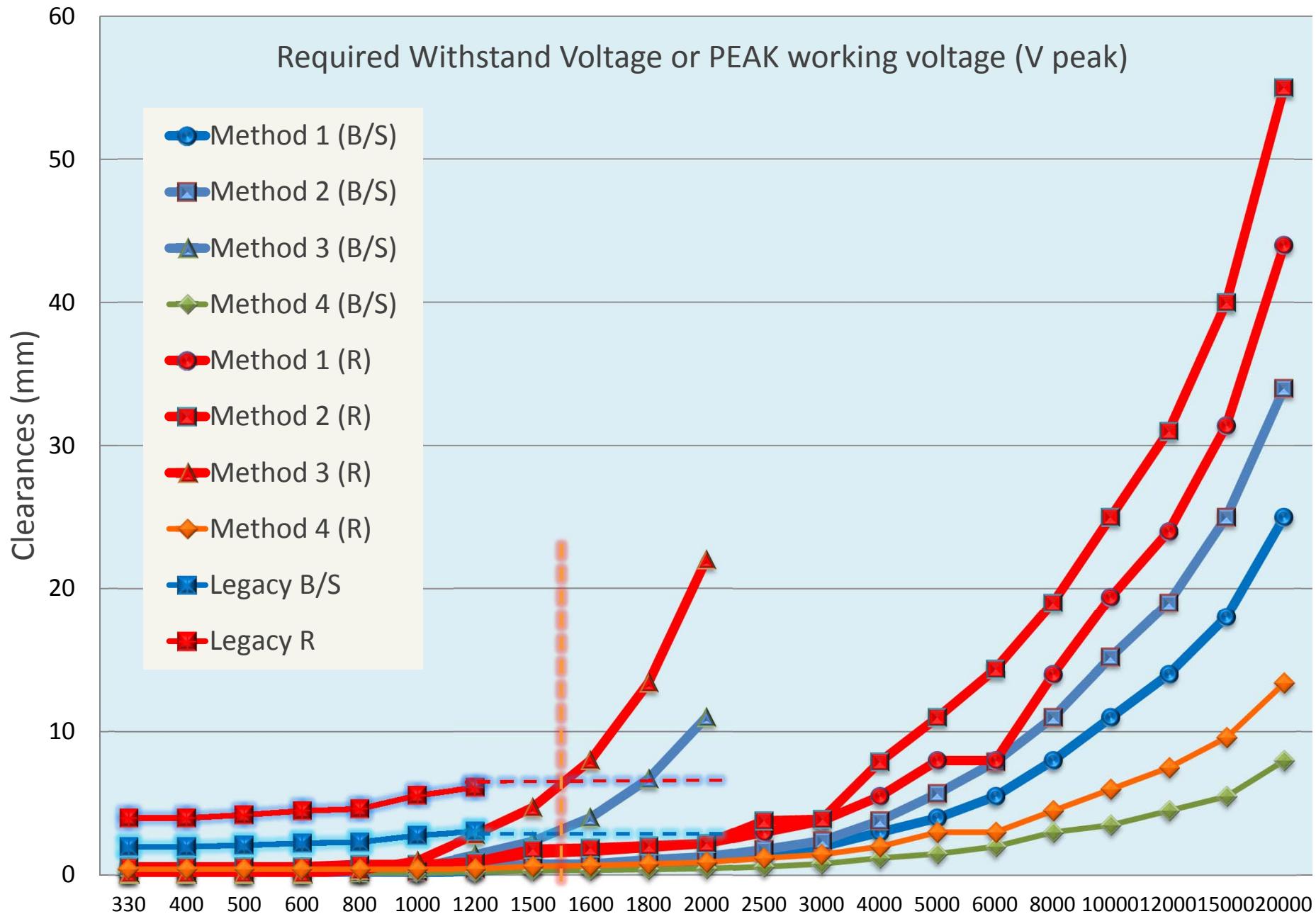
little effect on
small clearances.



inhomogeneous field distribution

- the corona discharge phenomenon in inhomogeneous fields (point-to-plane) is much more intense than homogeneous (plane-to-plane) that can be observed by naked eye.
- the worst-case U_b is about **50%** of that at power frequency.

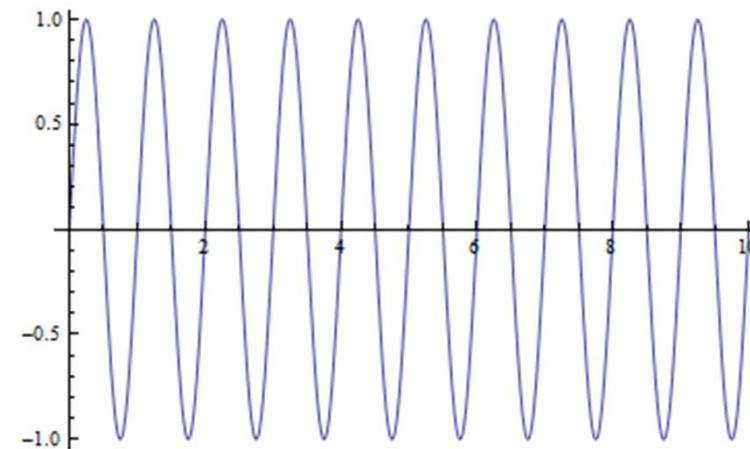
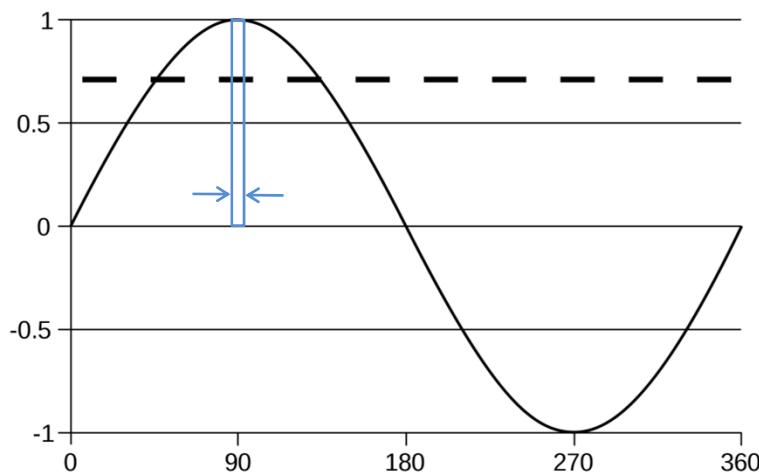


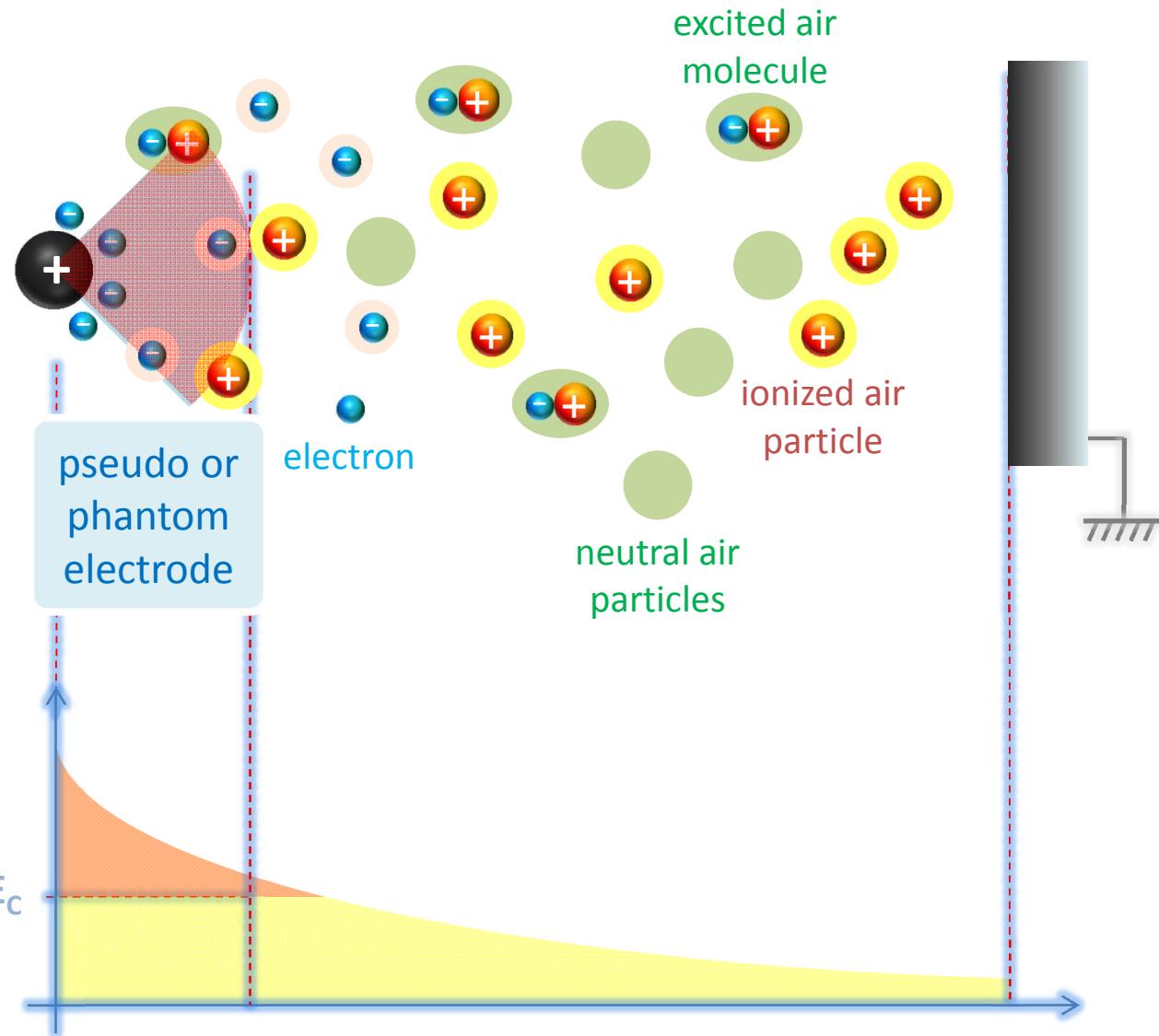


electrical breakdown in gases, i.e., clearances

typically takes more than 100 μs to develop.

- power frequency (10 ms):
 - a.c. (peak) and d.c. are virtually identical (98.77%).
- high frequencies (16.7 μs):
 - insufficient time to constitute complete breakdown.





if the clearances are large or at high frequencies, the ions might get trapped, resulting in the gradient distortion and consequent field strength weakening.



SOLID INSULATION



figure C.3 — breakdown at high frequency, solid insulation; $d = 0.75$ mm; comparison on short-time breakdown field strength E_b :

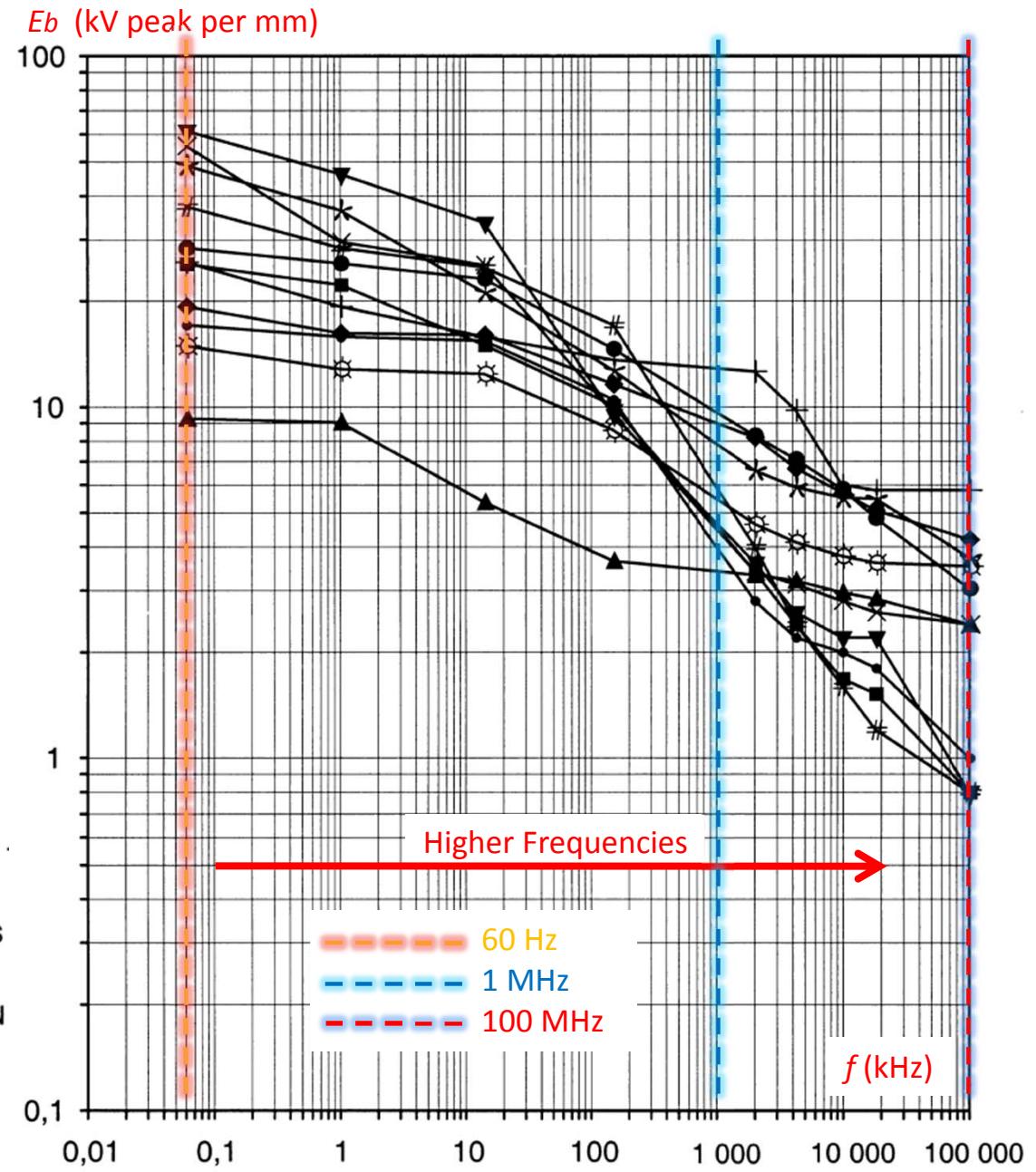
50/60 Hz = 1

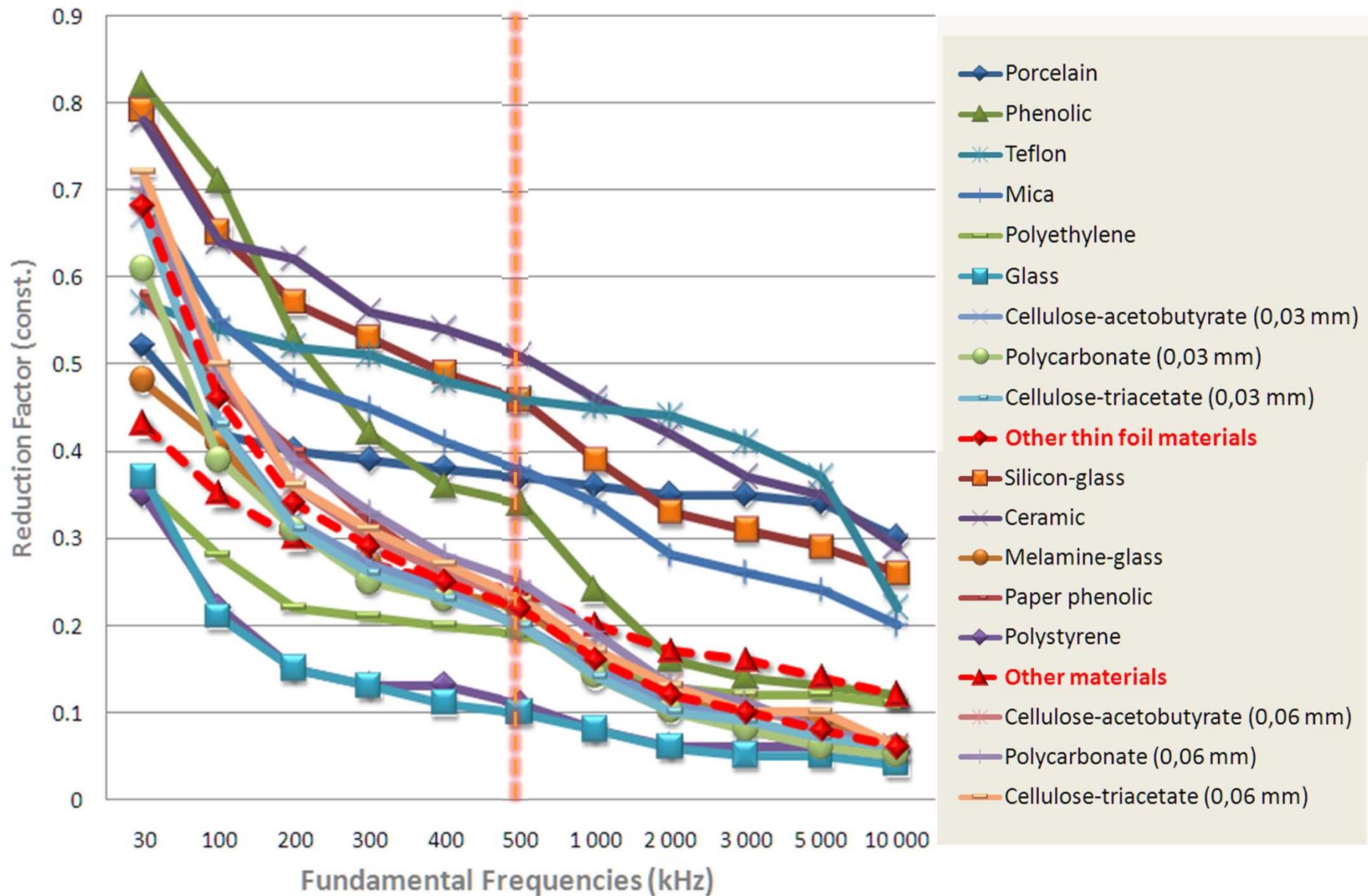
1 MHz = 0.66

100 MHz = 0.013

the bottom has not yet been reached!?

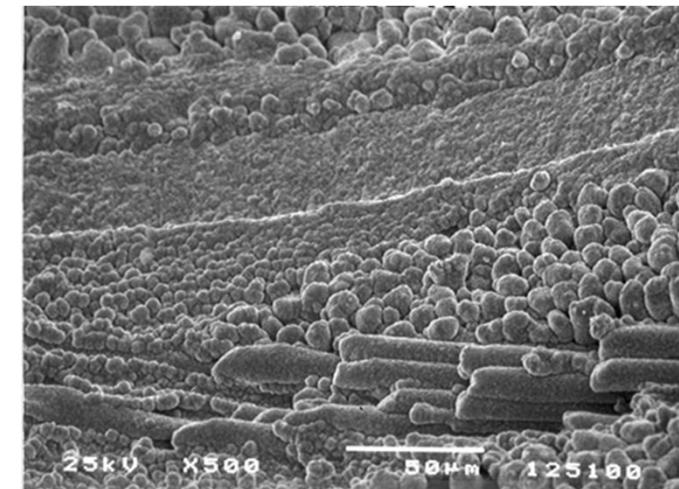
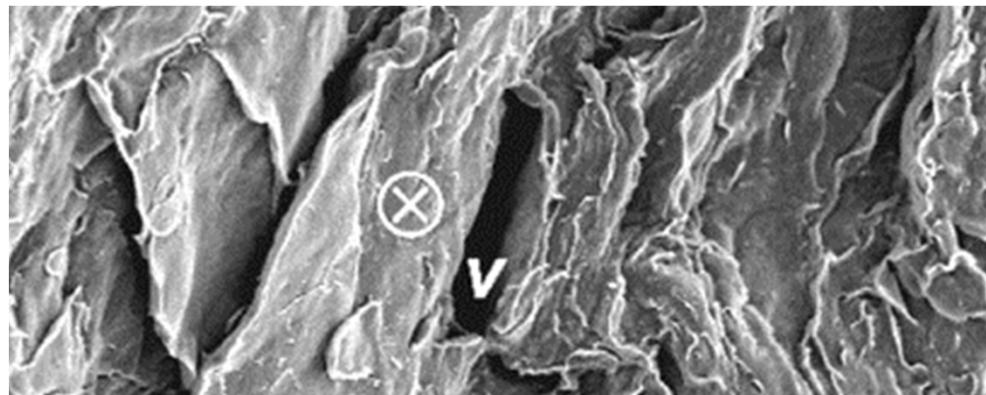
- PHENOLIC ▨ TEFILON ▲ POLYETHYLENE
- MICA ▼ GLASS ☀ SILICONE-GLASS
- × POLYSTYRENE ▽ CERAMIC ▴ PORCELAIN
- MELAMINE-GLASS # PAPER-PHENOLIC





solid insulation

- compared to air insulation, solid insulation provides at least a **ten-fold** increase in electric strength.
- however, in practice, a PD can occur in embedded voids or air gaps in solid dielectrics at a PD-inception voltage **far below** its breakdown voltage, reducing its voltage withstand ability, and likely resulting in the complete destruction of most solid dielectrics.



modeling a gas-filled void

$$C = \epsilon_r \epsilon_0 \frac{A}{d}$$

- ϵ_r (air) = 1.0006;
- ϵ_r (PC, polycarbonate) = 2.3;
- ϵ_r (FR-4) = 4.4;

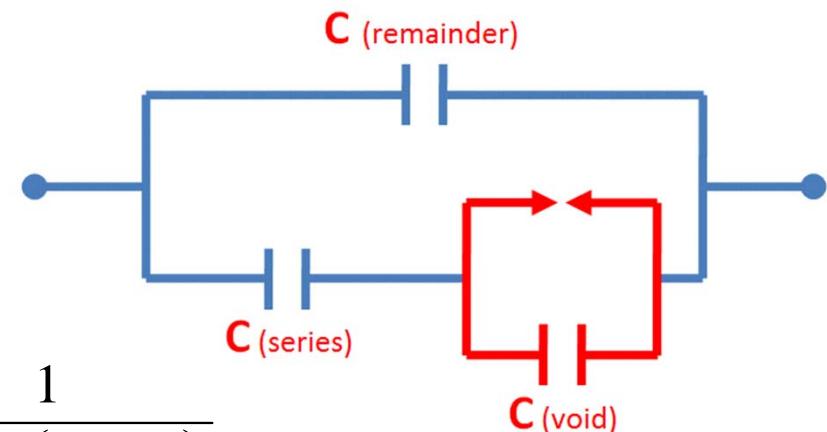
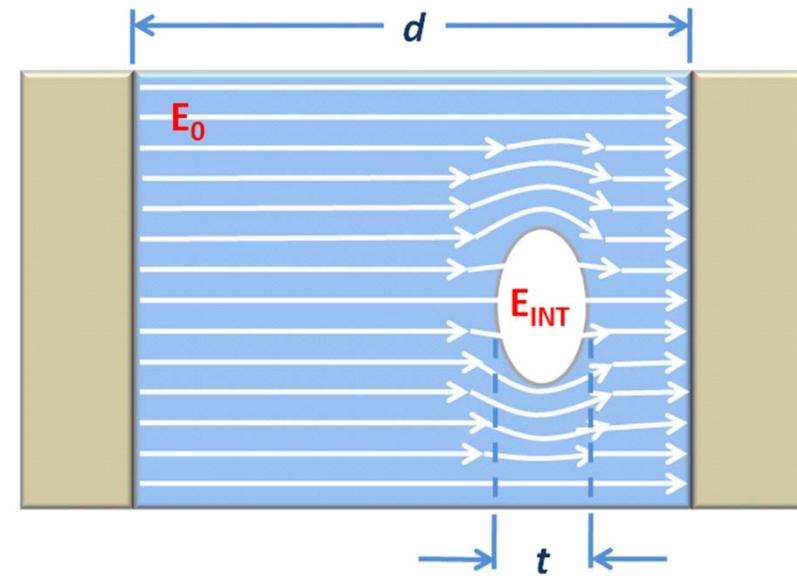
$$C_{(\text{remainder})} \gg C_{(\text{void})}$$

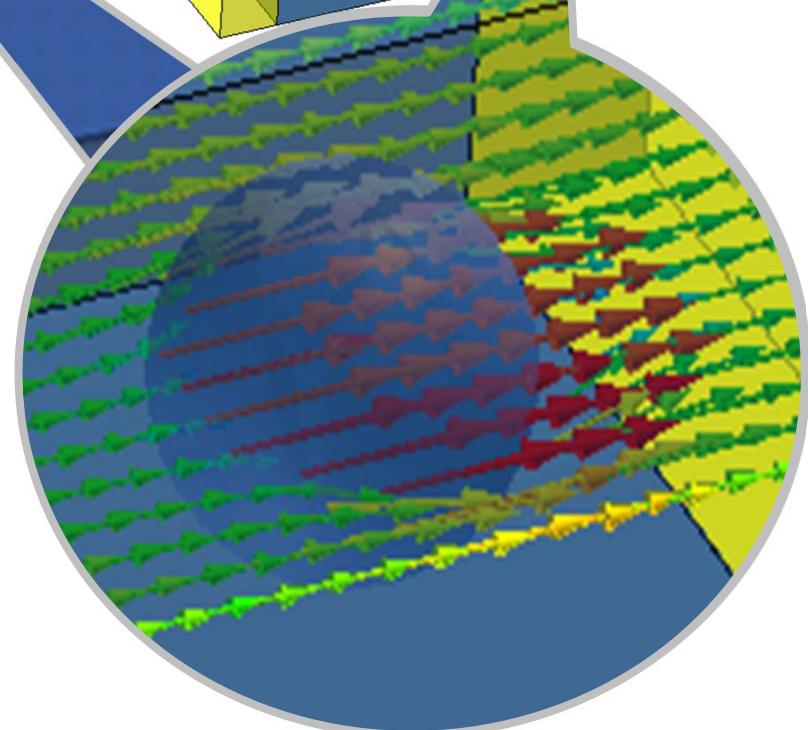
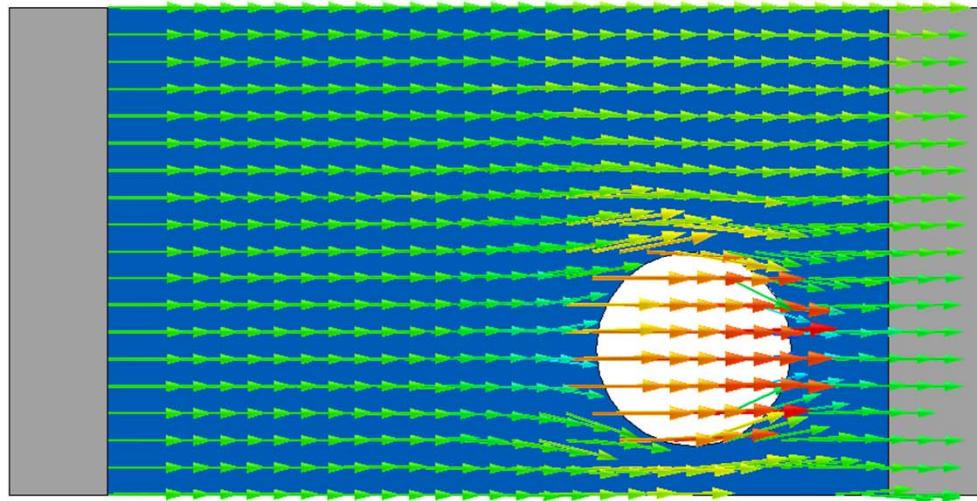
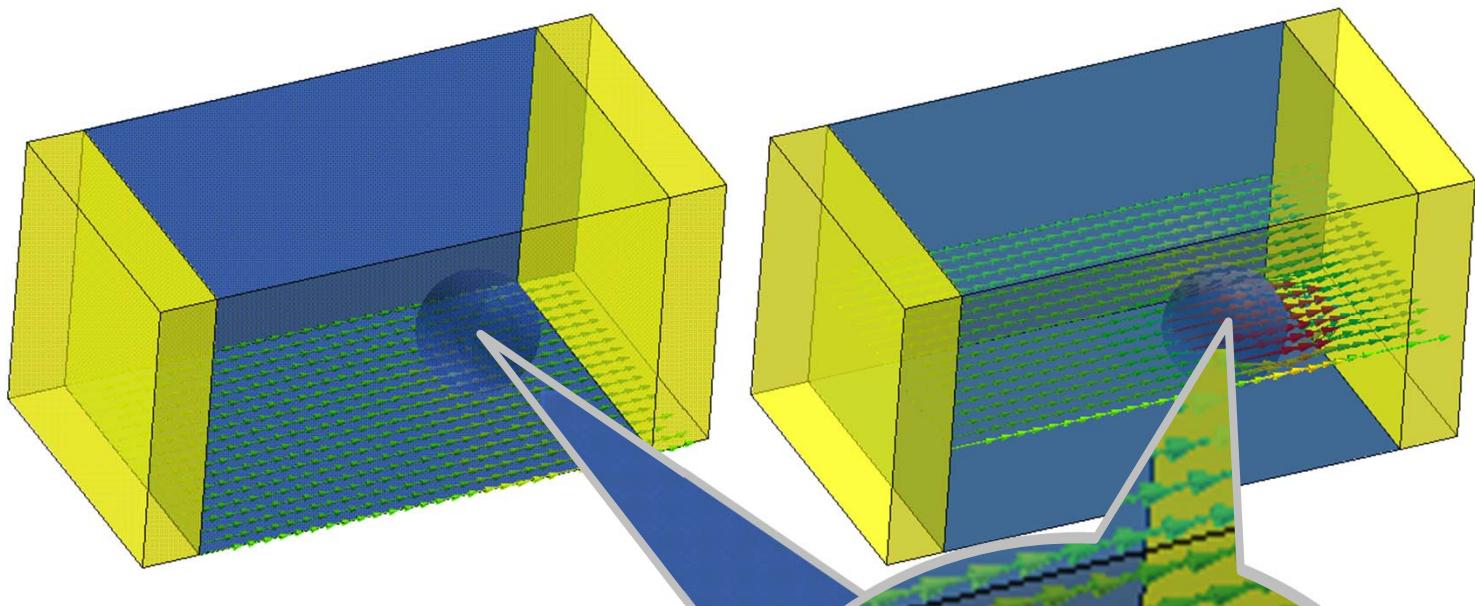
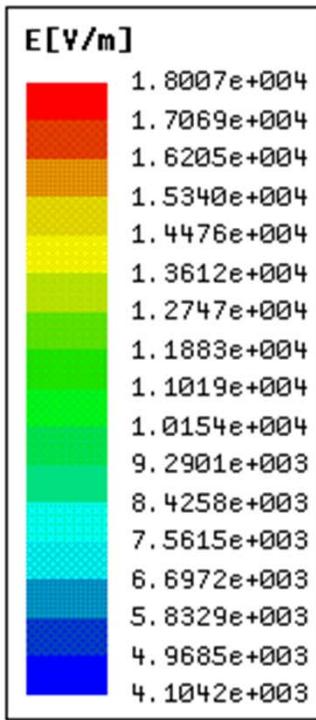
$$C_{(\text{void})} \gg C_{(\text{series})}$$

for any dielectric of the same size:

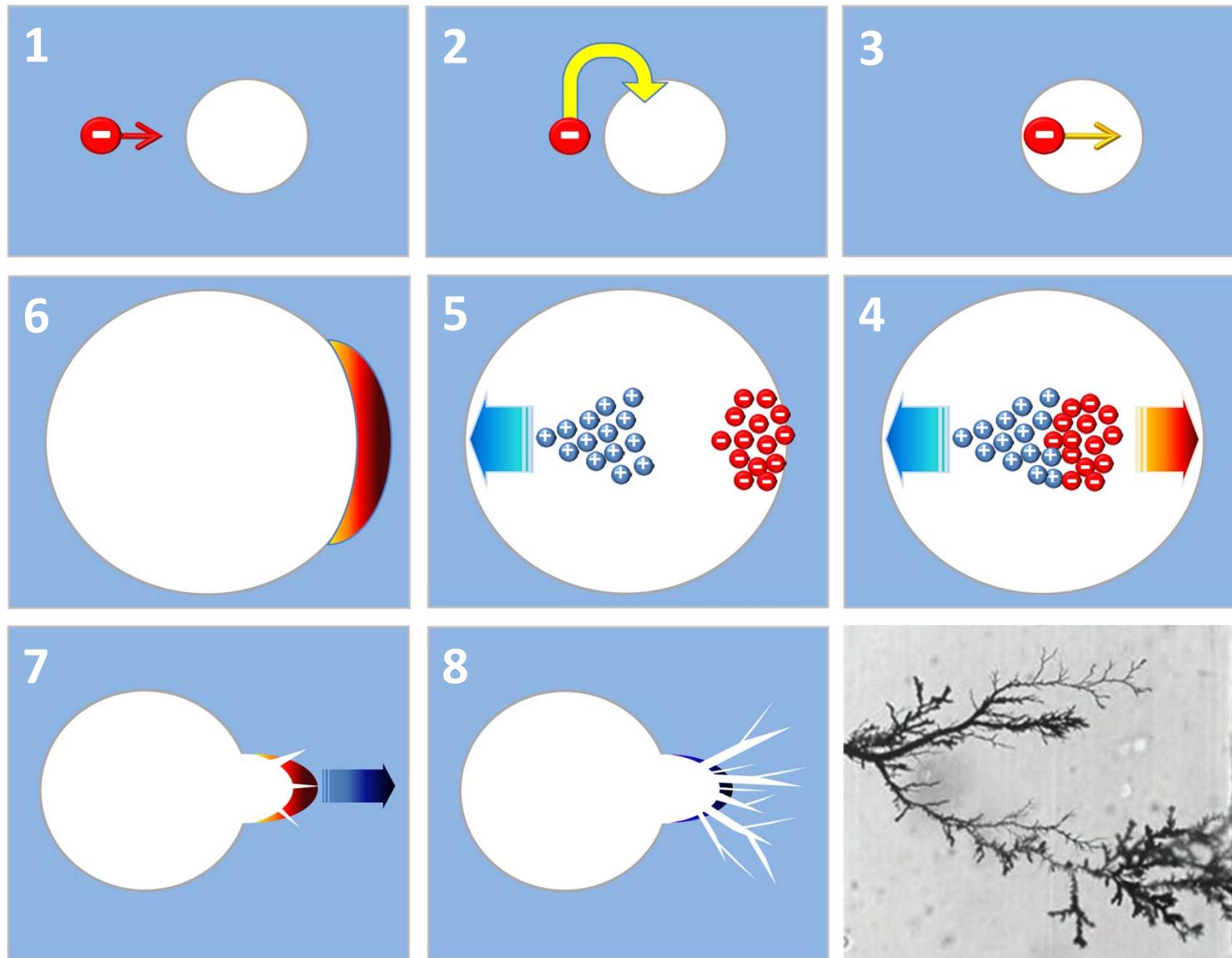
$$V_{(\text{void})} = \epsilon_r * V_{(\text{dielectric})}$$

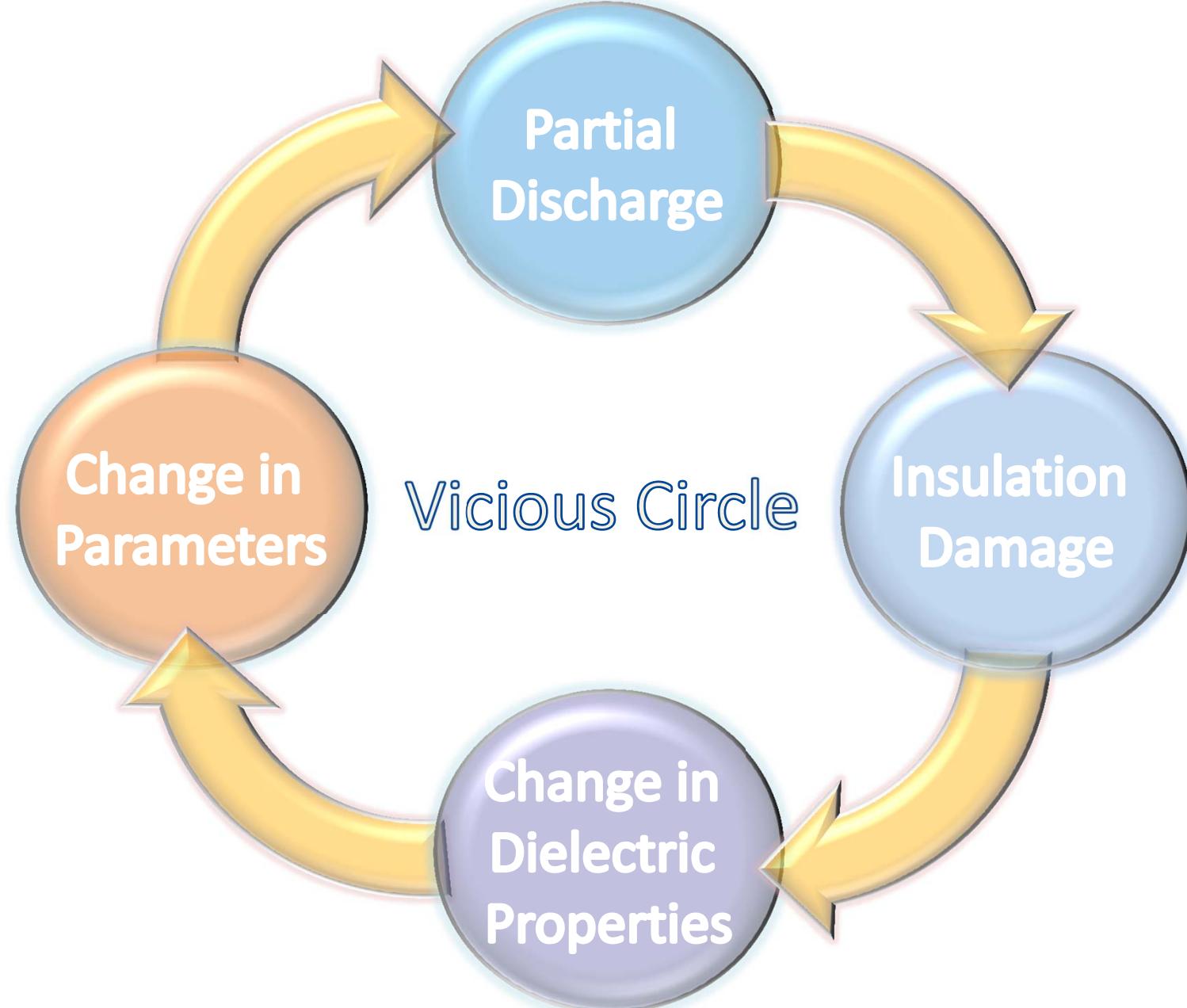
$$V_{(\text{void})} = V \frac{C_{(\text{series})}}{C_{(\text{series})} + C_{(\text{void})}} = V \frac{1}{1 + \frac{1}{\epsilon_r} \left(\frac{d}{t} - 1 \right)}$$





void-to-tree transition





CREEPAGE DISTANCES



the experiment

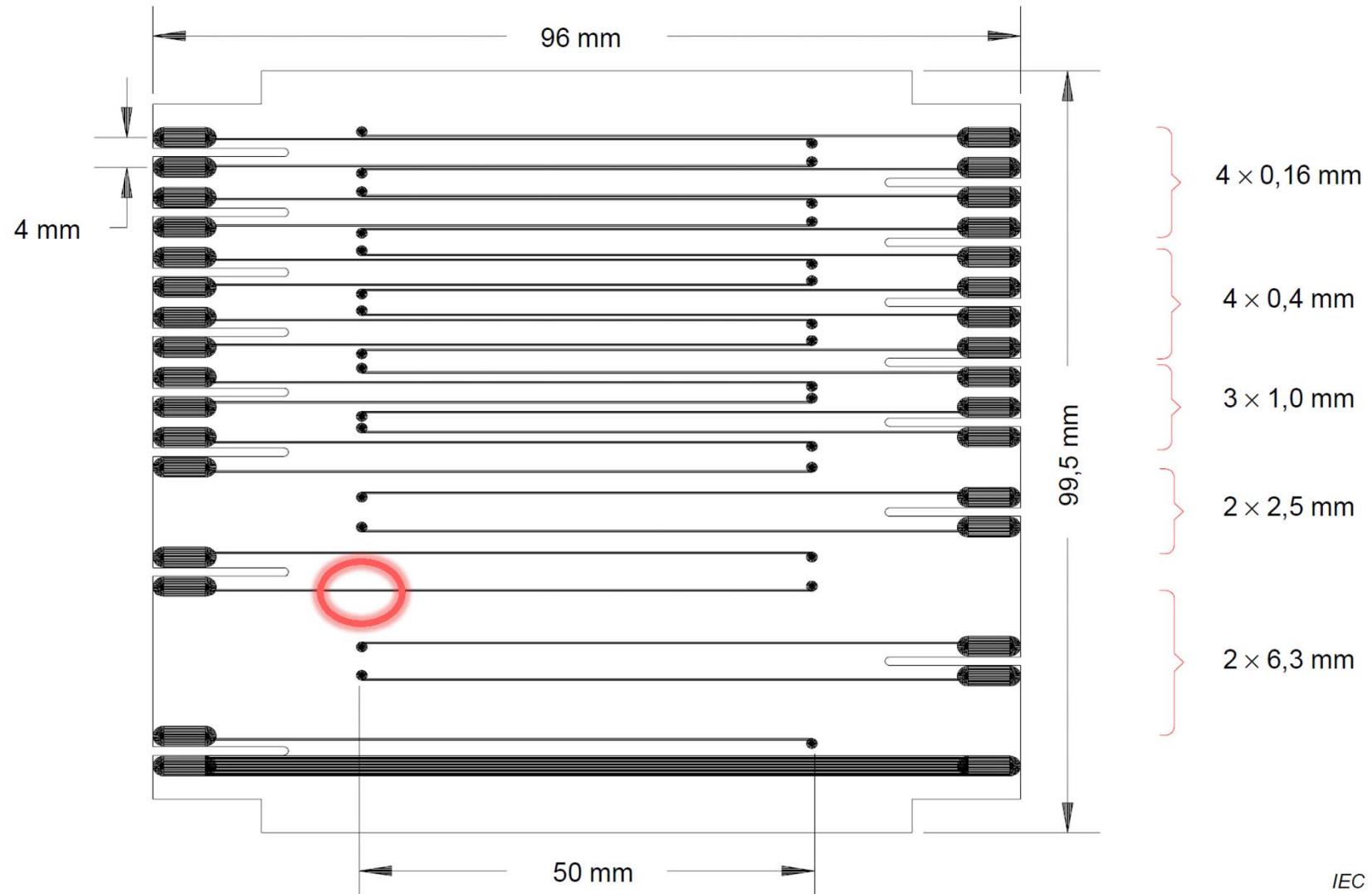


Figure B.3 — Breakdown Voltage (U_b)

U_b is less relevant
to frequency factor

larger creepage distances do not
add to the breakdown voltage, U_b

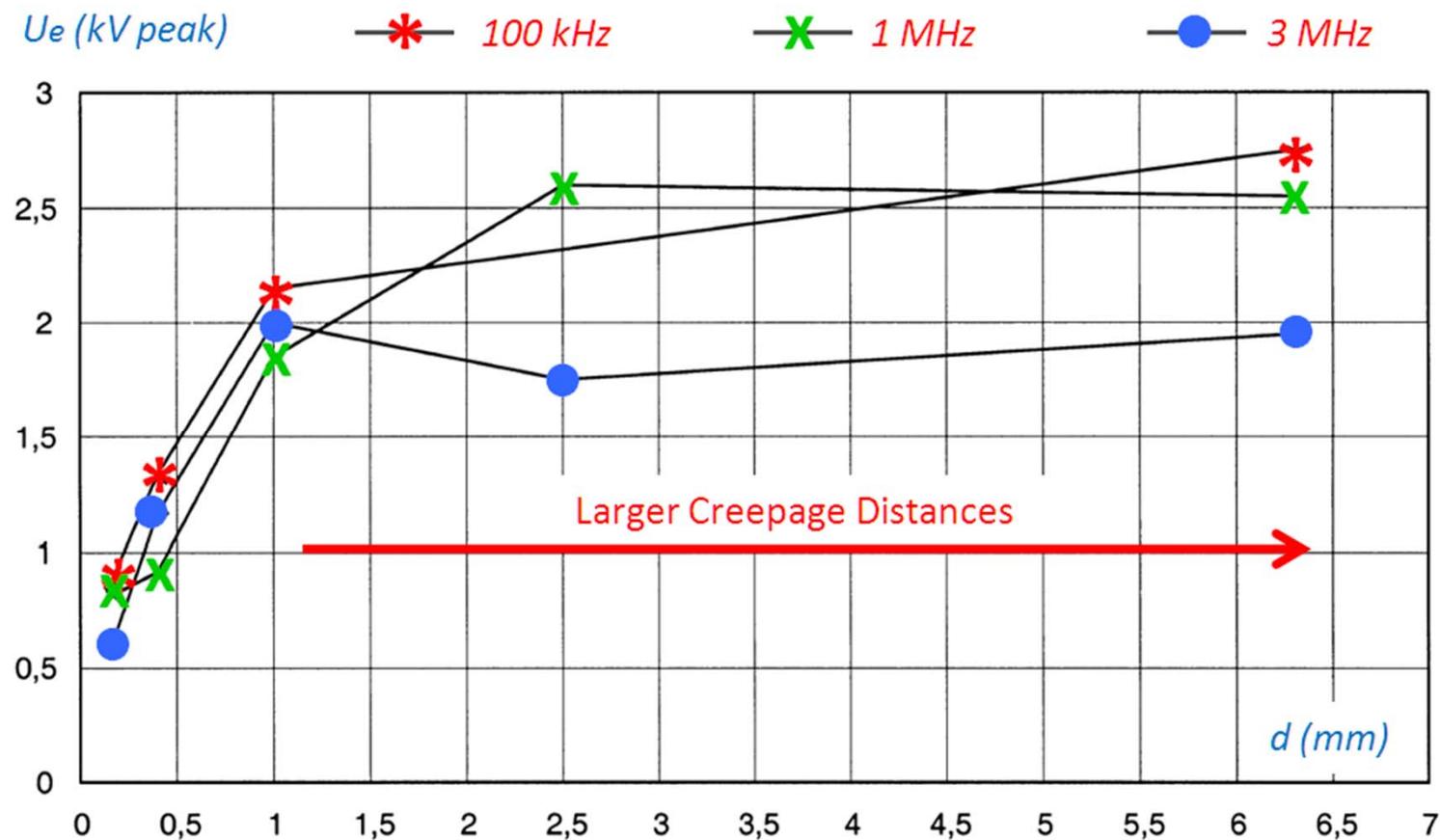
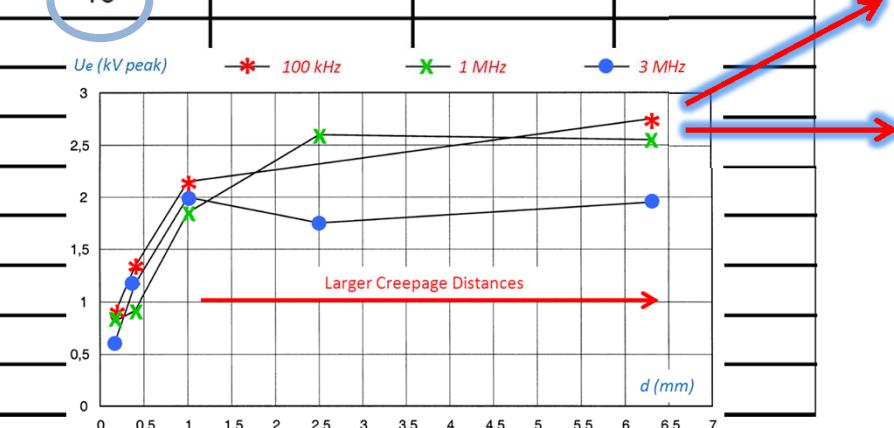
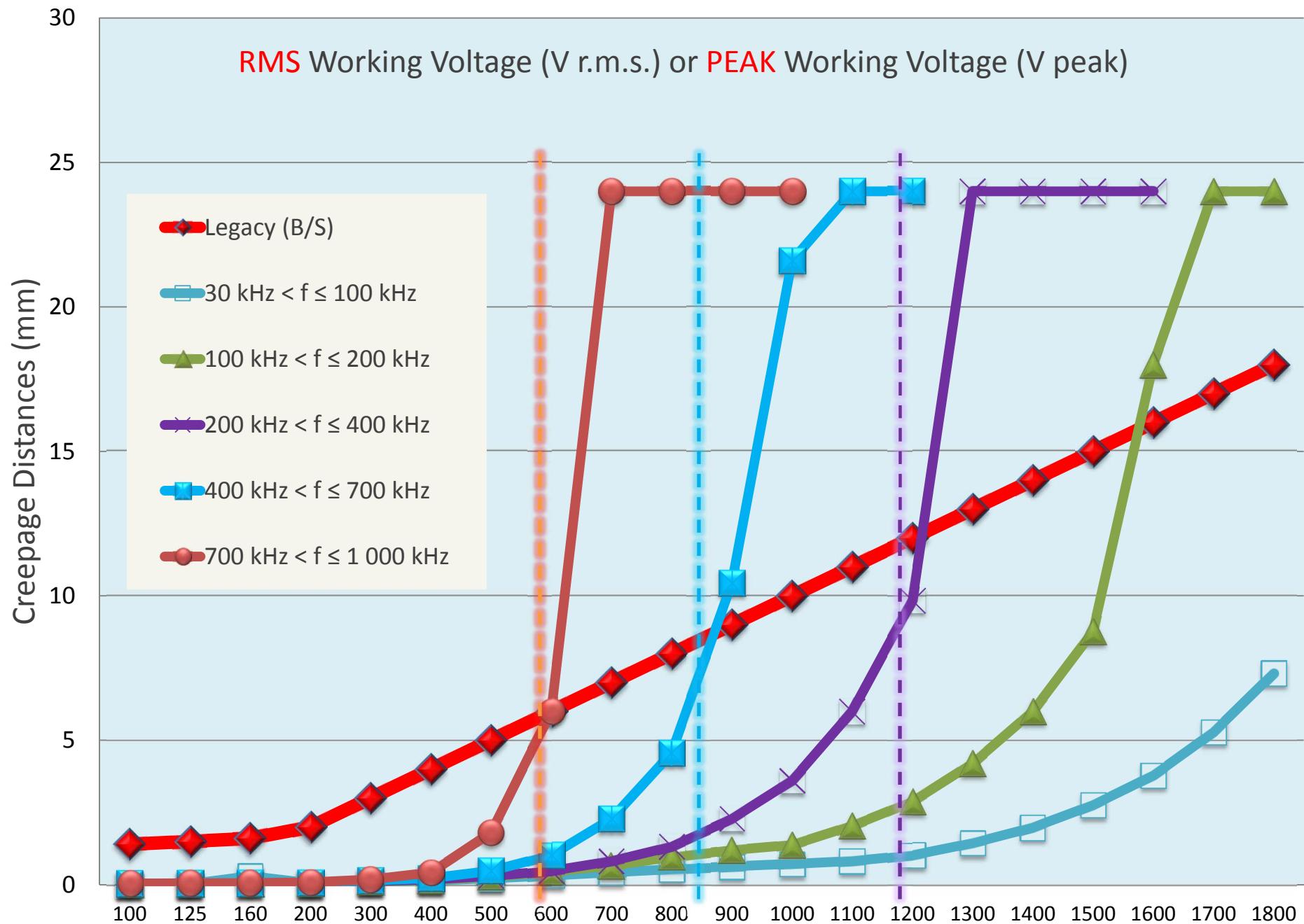


Table 2 – Minimum values of creepage distances for different frequency ranges

Voltage U_{peak} kV	Creepage distance ^{a)} mm						
	for $30 \text{ kHz} < f \leq 100 \text{ kHz}$	for $f \leq 0,2 \text{ MHz}^{\text{b)}$	for $f \leq 0,4 \text{ MHz}^{\text{b)}$	for $f \leq 0,7 \text{ MHz}^{\text{b)}$	for $f \leq 1 \text{ MHz}^{\text{b)}$	for $f \leq 2 \text{ MHz}^{\text{b)}$	for $f \leq 3 \text{ MHz}^{\text{b)}$
0,1	0,0167						0,3
0,2	0,042					0,15	2,8
0,3	0,083	0,09	0,09	0,09	0,09	0,8	20
0,4	0,125	0,13	0,15	0,19	0,35	4,5	
0,5	0,183	0,19	0,25	0,4	1,5	20	
0,6	0,267	0,27	0,4	0,85	5		
0,7	0,358	0,38	0,68	1,9	20		
0,8	0,45	0,55	1,1	3,8			
0,9	0,525	0,82	1,9	8,7			
1	0,6	1,15	3	18			
1,1	0,683	1,7	5				
1,2	0,85	2,4	8,2				
1,3	1,2	3,5					
1,4	1,65	5					
1,5	2,3	7,3					
1,6	3,15						
1,7	4,4						
1,8	6,1						

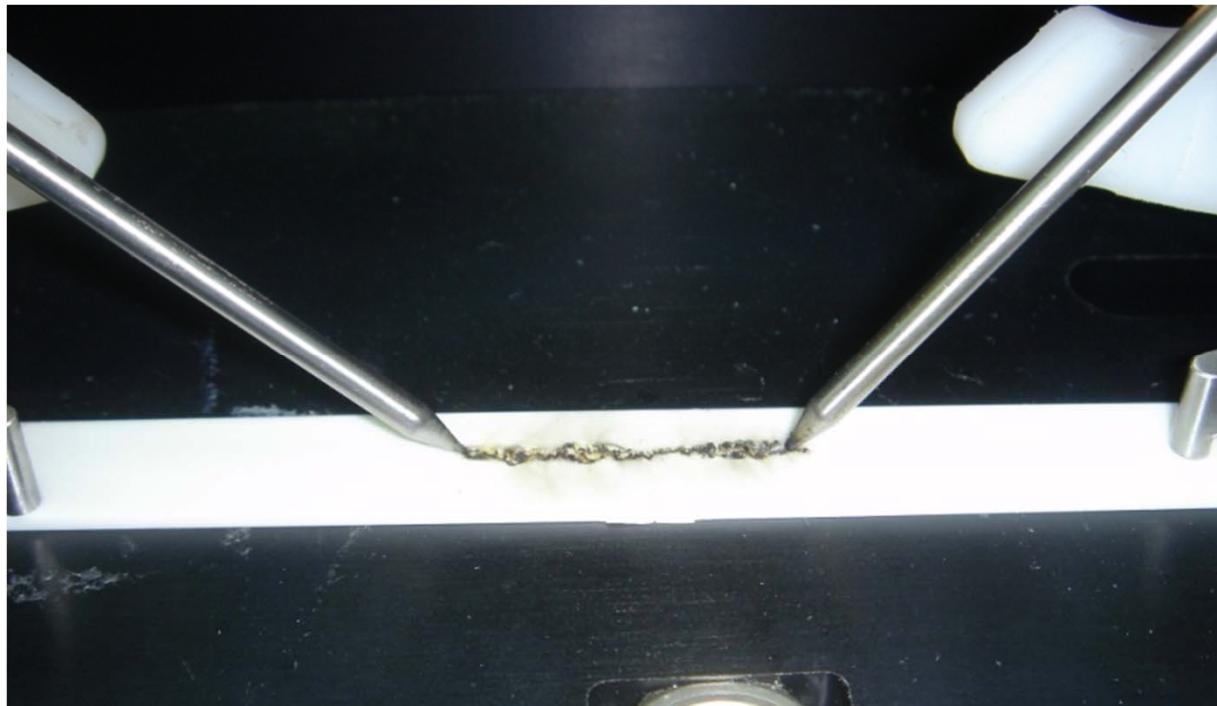




surface breakdown, i.e., creepage distances

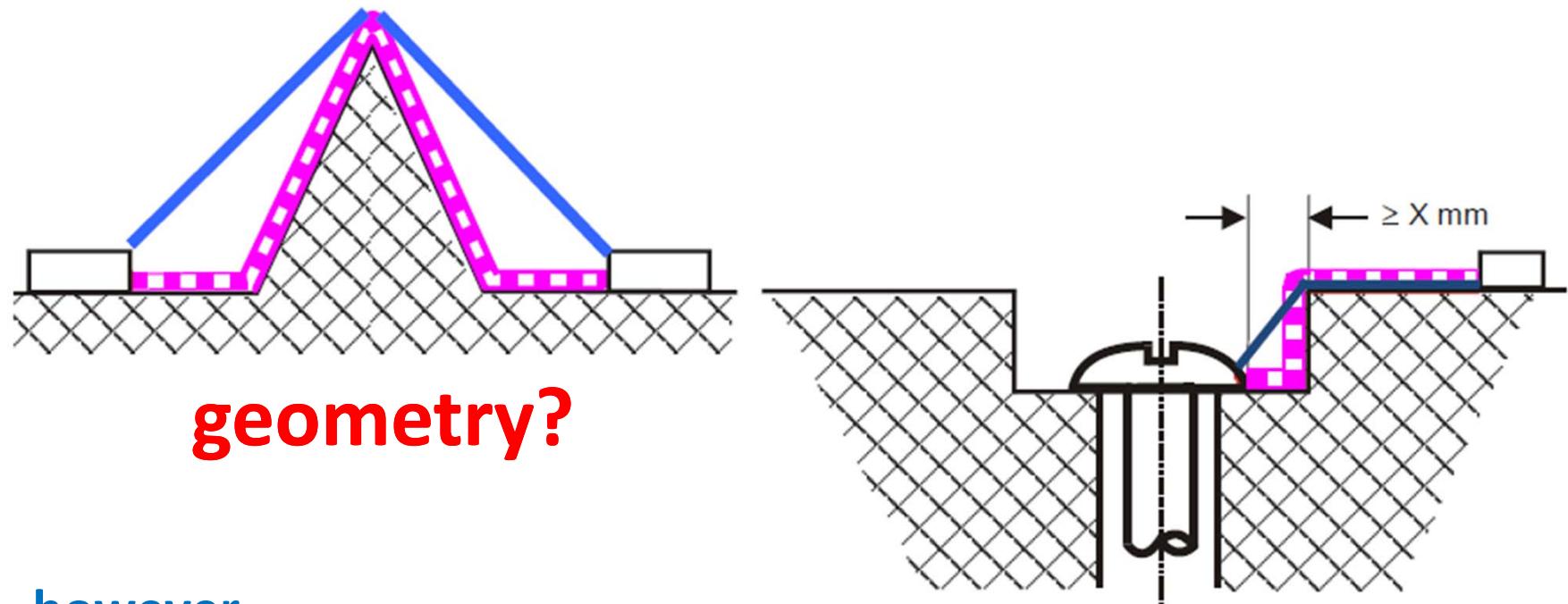
unlike clearances, creepage distances and solid insulation are **NOT** replenishable — permanent damage such as puncture or carbonized tracking, is likely.

- in this sense, clearances are less vulnerable to PD.



please humor me while I speculate...

what does it mean by saying "**creepage distances must be equal to or greater than clearances?**"

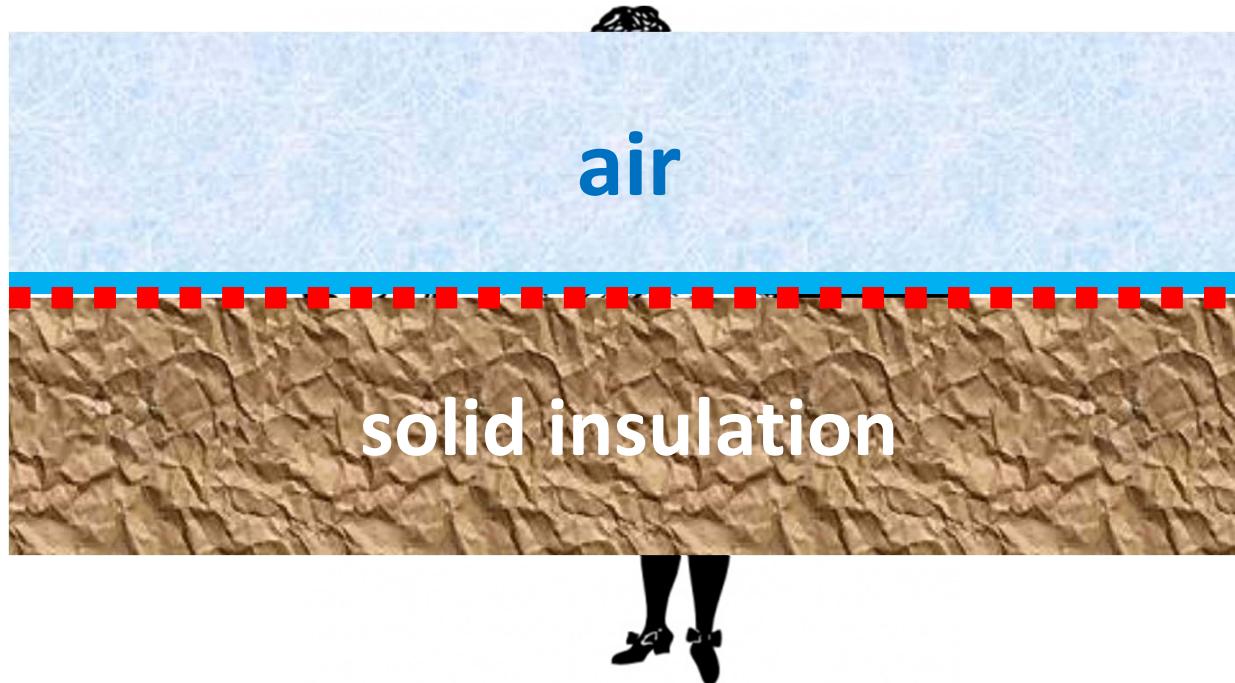


geometry?

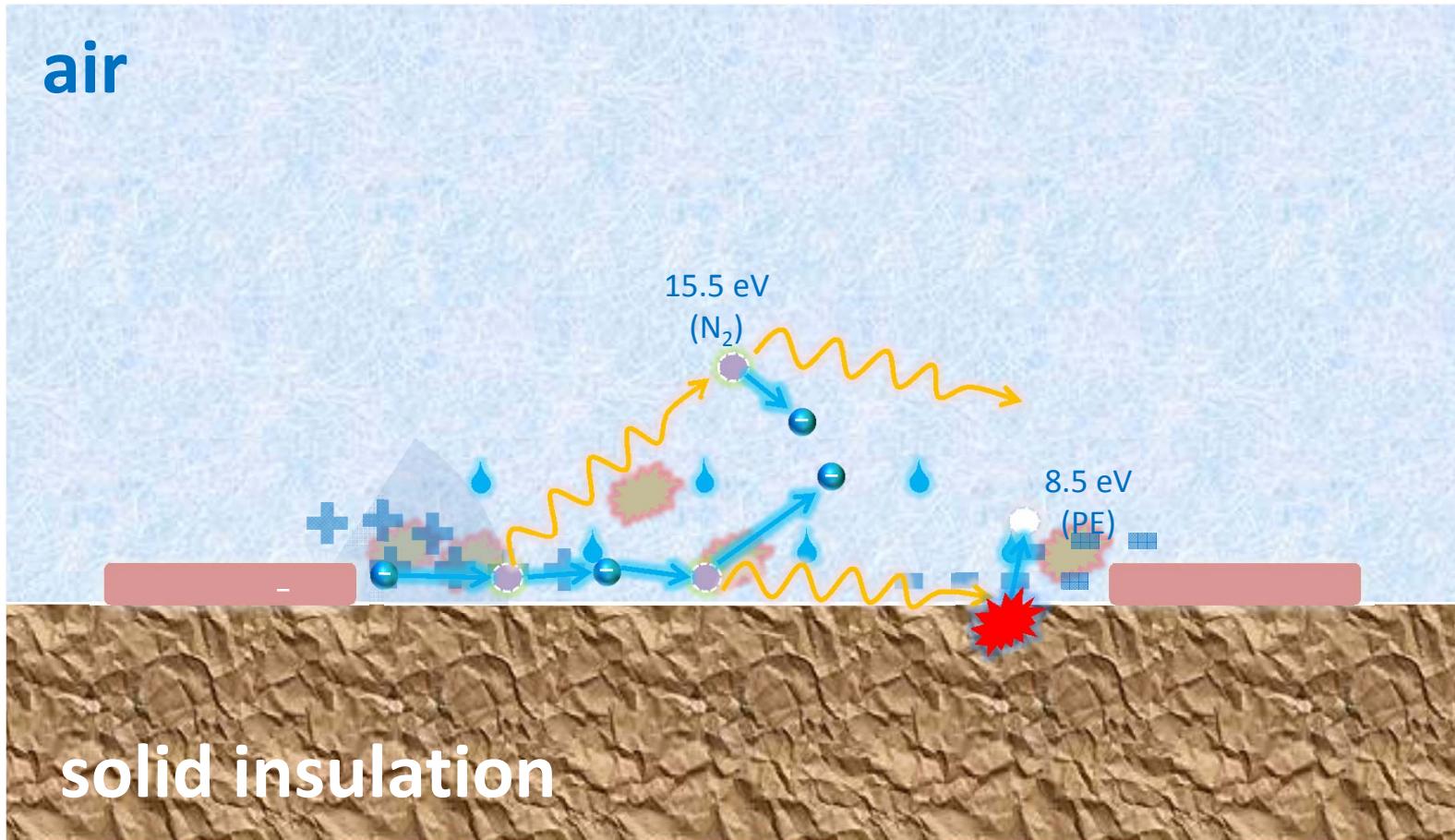
however,
from this aspect it is difficult to understand
what is the relationship between CL and CR.

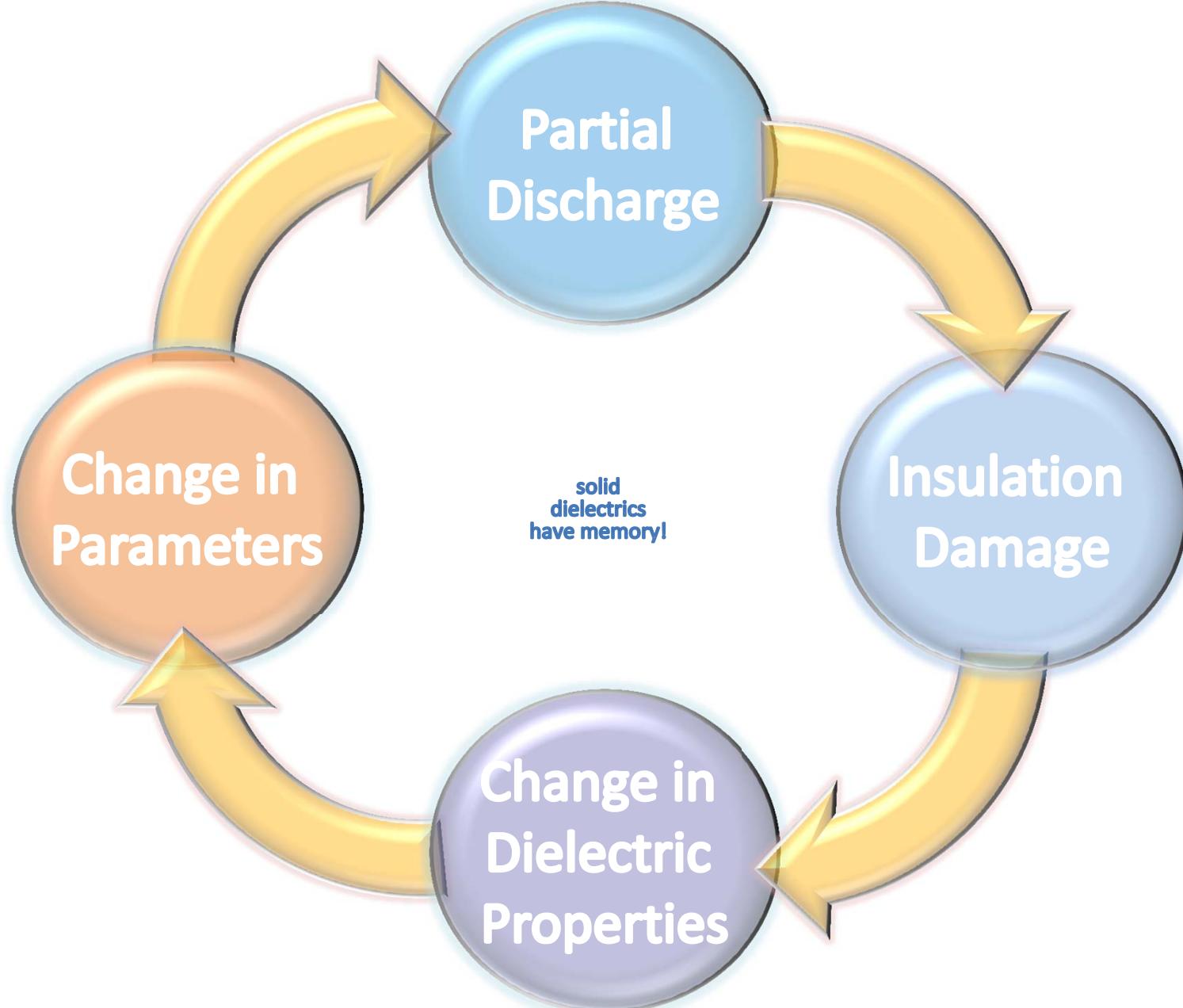


I would say when we're talking about the **creepage distances** we have to keep in mind that we're talking about **clearances** as well.



how creepage distances and clearances interact with each other?







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謝謝大家的時間！

